addenda and errata

Direct protein crystallization on ultrathin membranes for diffraction measurements at X-ray free-electron lasers. Corrigendum

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‡ As of March 2019 the PSI domain corresponding author's address became obsolete; prospective questions on the content of the article can be directed to nadia.opara@gmail.com.

Errors in the article by Opara, Martiel, Arnold, Braun, Stahlberg, Makita, David & Padeste [*J. Appl. Cryst.* (2017), **50**, 909–918] are corrected.

In the article by Opara *et al.* (2017), the chemical formula of the silicon nitride was given erroneously. No detailed structural analysis was performed, and no experimental evidence is provided to justify the claim that all of the silicon nitride membranes used in the presented experiments had stoichiometric composition (Yang & Pham, 2018). Therefore, the formula describing the specific case Si_3N_4 should be replaced with the generic formula Si_xN_y.

In addition, there was a typographical error in the unit of ultrapure water resistivity, which should be $M\Omega$ cm.

References

Opara, N., Martiel, I., Arnold, S. A., Braun, T., Stahlberg, H., Makita, M., David, C. & Padeste, C. (2017). *J. Appl. Cryst.* **50**, 909–918.
Yang, C. & Pham, J. (2018). *Silicon*, **10**, 2561–2567.